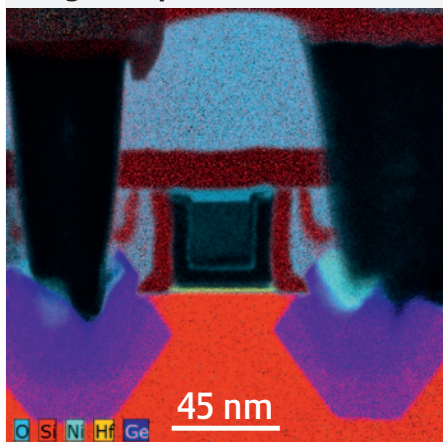


ChemiSTEM™ technology

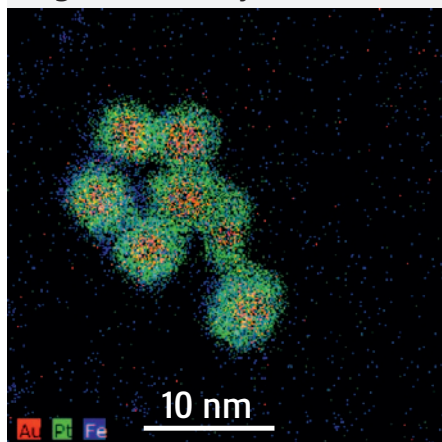
A revolution in EDX analytics

Large map, all elements



45 nm PMOS structure
600 x 600 pixels
Drift correction applied

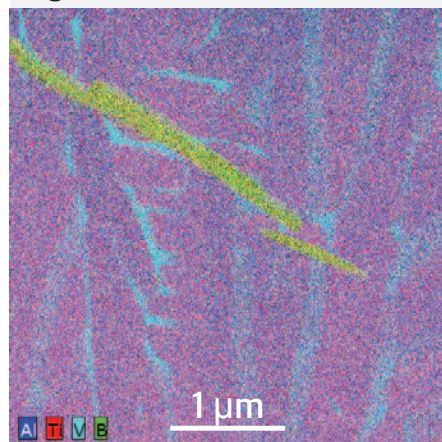
High sensitivity



Au/Pt(Fe) core/shell particles < 5 nm
300 x 300 pixels recorded in < 4 min

Sample courtesy of C. Wang, V. Stamenkovic,
N. Markovic and N.J. Zaluzec, Argonne
National Laboratory

Light element detection



Boron distribution in TiB/TiAl
512 x 512 pixels recorded in < 5 min
100 μsec dwell time; multiple frames

Sample courtesy of
Ohio State University



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- Ultimate speed: elemental maps in minutes
- Highest sensitivity for light elements and low concentrations

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$\text{Ca}_3\text{Co}_4\text{O}_9$ (110)

Data courtesy of Dr. Robert Klie,
University of Illinois at Chicago

Visualization of hydrogen atomic columns in YH_2 by
ABF imaging (Y = red, H = green) Data courtesy of
Ryo Ishikawa and Dr. Eiji Abe (The University of Tokyo)

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